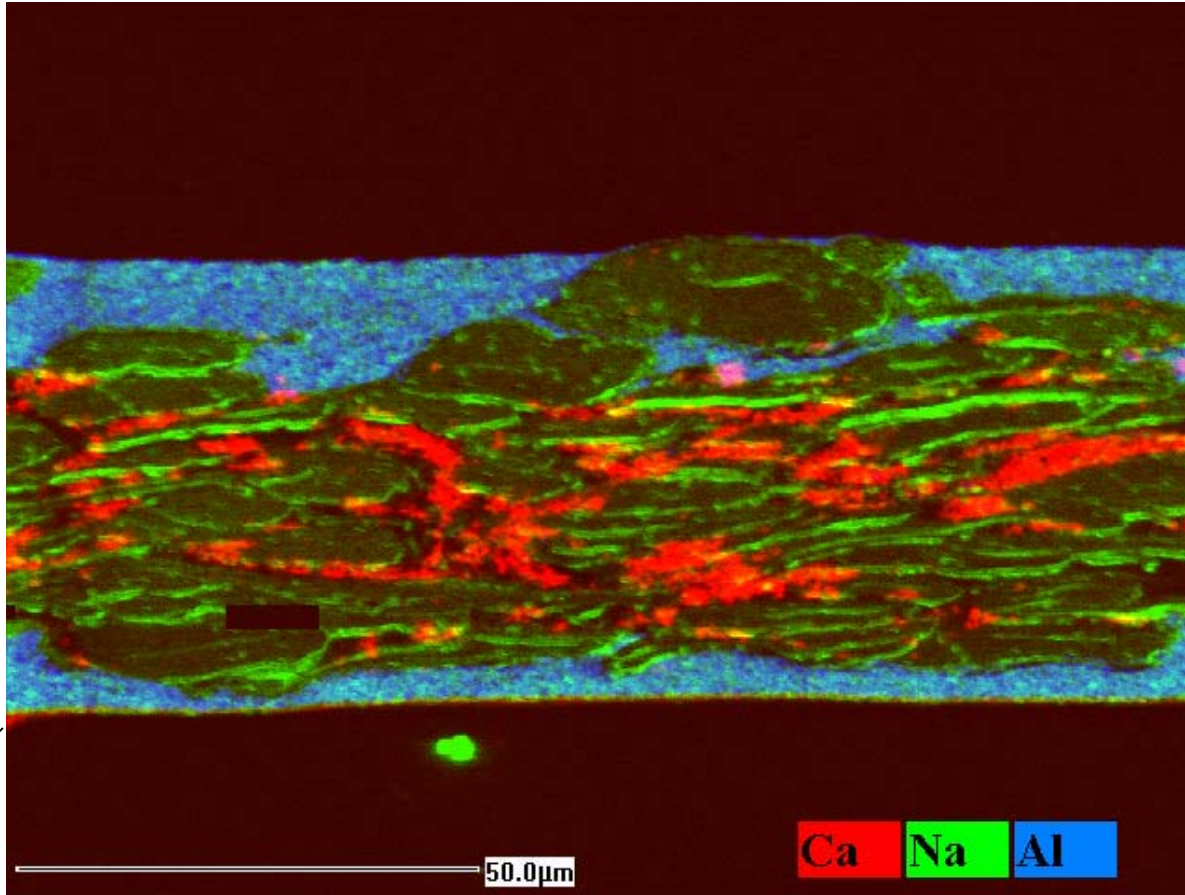


SIMS Sections to see ink component distribution

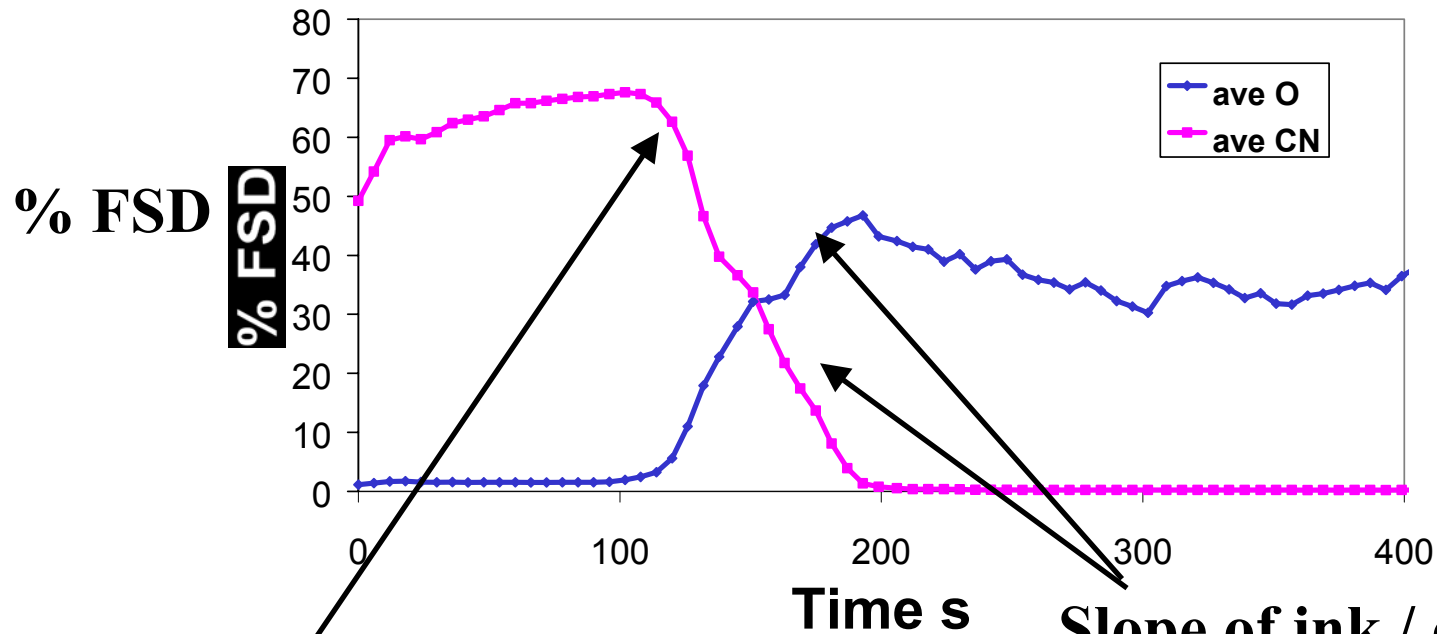
Imaging SIMS can give high resolution ion fragment maps



Ink pigment on top of the coating layer - no penetration

Depth Profiling - shows interface between ink and paper

High resolution compositional data can be obtained by depth profiling in the Z direction. →

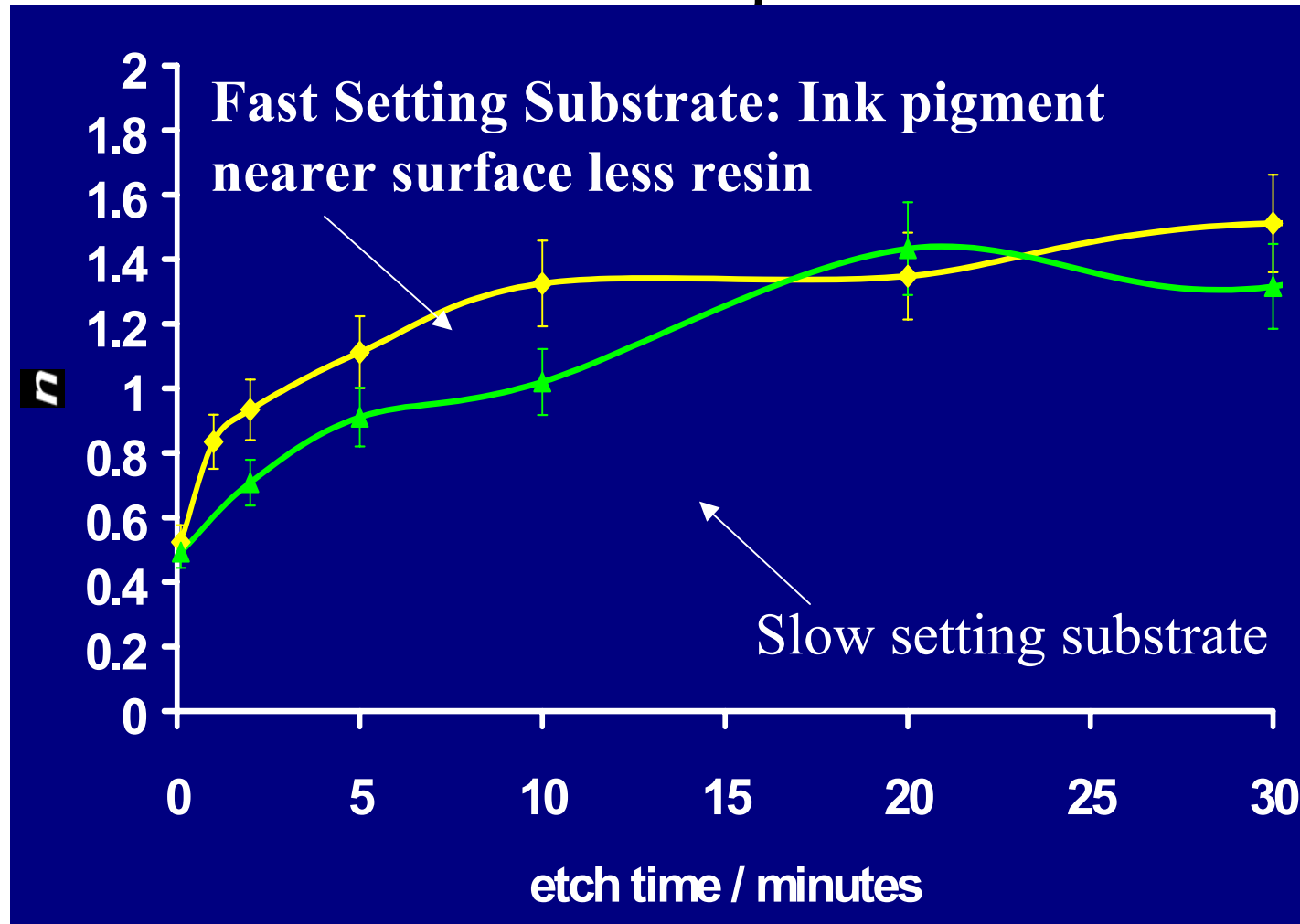


CN - trace indicates ink film thickness

Slope of ink / coating interface modelled using microroughness - CN- does not penetrate coating

XPS Analysis shows evidence of resin depletion

Etching XPS can differentiate small differences in resin / pigment distribution at print surface



Dalton J.S., Preston J.S., Heard P.J., Allen G.C., Elton N.J., Husband J.C., "Investigation into the distribution of ink components throughout printed coated paper – Part 2: Utilising XPS and SIMS", "Colloids and Surfaces A: Physicochemical and Engineering Aspects" Elsevier Science., 205 (2002), 199-213